

Docket No.: W&B-INF-952

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Applicant : ROBERT KAISER ET AL.
Filed : CONCURRENTLY HEREWITH
Title : INTEGRATED CIRCUIT HAVING A DATA PROCESSING UNIT
AND A BUFFER MEMORY

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent 5,313,424 (Adams et al.), dated May 17, 1994;

German published Non-Prosecuted Patent Application DE 197 08 965 A1 (Zettler), dated September 24, 1998, data storage;

Tarr M. et al.: "Defect Analysis System Speeds Test and Repair of Redundant Memories", Electronics, January 12, 1984, pp. 175, 177, 179;

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "W. Stemer", written over a horizontal line.

For Applicants

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FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))Attorney Docket No.: W&B-INF-952
Appl. No.

Applicant ROBERT KAISER ET AL.

Filing Date December 20, 2001
Group Art Unit

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	5,313,424	5/17/94	Adams et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J	DE 197 08 965 A1	9/24/98	Germany			
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

		Tarr M. et al.: "Defect Analysis System Speeds Test and Repair of Redundant Memories", Electronics, January 12, 1984, pp. 175, 177, 179;

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.